A1

Substitute for form 1449B/PTO **INFORMATION DISCLOSURE STATEMENT BY APPLICANT** Date Submitted: July 16, 2003 *(use as many sheets as necessary)*		**Complete if Known**	
		Application Number	Unassigned
		Filing Date	07/16/2003
		First Named Inventor	Junichi TAKEUCHI
		Group Art Unit	~~Unassigned~~ 2129
		Examiner Name	~~Unassigned~~ Omar F. Fernandez
Sheet	1	of	1	Attorney Docket Number	040405-0363

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code[2] *(if known)*			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document			Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T[6]
		Office[3]	Number[4]	Kind Code[5] *(if known)*				

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[6]
/OFR/	A1	P. BURGE, et al., "Detecting Cellular Fraud Using Adaptive Prototypes.", (Proceedings of AI Approaches to Fraud Detection and Risk Management), pp. 9-13, 1997.	
/OFR/	A2	K. YAMANISHI, et al., "On-line Unsupervised Outlier Detection Using Finite Mixtures with Discounting Learning Algorithms", (Proceedings of the sixth ACM SIGKDD International Conference onKnwoledge Discovery and Data Mining, ACM Press), pp. 320-324, 2000.	
/OFR/	A3	U. MURAD, et al., "Unsupervised Profiling for Identifying Superimposed Fraud", (Proceedings of 3rd European conference on Principles and Practice of Knowledge Discovery in Database), pp. 251-261, 1999.	
/OFR/	A4	B. GUTHERY, "Partition Regression", in Journal of American Statistical Association, vol. 69, pp. 945-947, 1974.	
/OFR/	A5	M. HUŠKOVÁ, "NONPARAMETRIC PROCEDURES FOR DETECTING A CHANGE IN SIMPLE LINEAR REGRESSION MODELS", *Applied Change Point Problems in Statistics*, Nova Science Publishers, Inc., 1995.	
/OFR/	A6	V. GURALNIK, et al., "Event Detection from Time Series Data", (Proceedings of the ACM SIGKDD International Conference on Knowledge Discovery and Data Mining, ACM Press), pp. 32-42, 1999.	

Examiner Signature	/Omar Fernandez Rivas/	Date Considered	04/06/2007

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Substitute for form 1449B/PTO	Complete If Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT Date Submitted: March 7, 2006 (use as many sheets as necessary)	Application Number	10/619,626
	Filing Date	7/16/2003
	First Named Inventor	Junichi TAKEUCHI
	Group Art Unit	2129
	Examiner Name	Fernandez Rivas, Omar F.
Sheet 1 of 1	Attorney Docket Number	040405-0363

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Examiner Initials*	Cite No.[1]	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		Office[3]	Number[4]	Kind Code[5] (if known)				
/OFR/	A1	JP	2001-101154		NEC Corporation	April 13, 2001		ABS
/OFR/	A2	GB	2361336		NEC Corporation	October 17, 2001		

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/OFR/	A3	Vasundhara Puttagunta, et al., Adaptive Methods for Activity Monitoring of Streaming Data, Proceedings of the 2002 International Conferences on Machine Learning and Applications (ICMLA '02), U.S.A., CSREA Press, June 24, 2002, pp. 197-203, [Searched February 2, 2006], Internet <URL, http://www.csee.umbc.edu/~kalpakis/homepage/papers/kalpakisICMLA02.pdf>	
/OFR/	A4	Kenji Yamanishi et al., "Data Mining with Statistic Outlier Detection and Application to Network Invasion Detection," Technical Research Reports of the Institute of Electronics, Information and Communication Engineers, Japan, the Institute of Electronics, Information and Communication Engineers, June 14, 2002, Vol. 102, No. 132, pp. 19-24	
/OFR/	A5	Ikuo Yonemoto et al., "On-line Estimation of Probability Density Function Using Information Quantity Standard," Technical Research Reports of the Institute of Electronics, Information and Communication Engineers, Japan, the Institute of Electronics, Information and Communication Engineers, December 18, 1998, Vol. 98, No. 490, pp. 189-194	

Examiner Signature	/Omar Fernandez Rivas/	Date Considered	04/06/2007

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